

### **MOSFET**

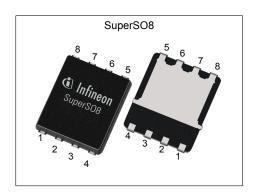
### OptiMOS<sup>™</sup>5 Power-Transistor, 80 V

### **Features**

- Optimized for high performance SMPS, e.g. sync. rec.
- 100% avalanche testedSuperior thermal resistance
- N-channel
- Qualified according to JEDEC<sup>1)</sup> for target applications
  Pb-free lead plating; RoHS compliant
  Halogen-free according to IEC61249-2-21

Table 1 **Key Performance Parameters** 

Parameter	Value	Unit	
V <sub>DS</sub>	80	V	
R <sub>DS(on),max</sub>	5.2	mΩ	
I <sub>D</sub>	95	A	
Qoss	39	nC	
Q <sub>G</sub> (0V10V)	32	nC	











Type / Ordering Code	Package	Marking	Related Links
BSC052N08NS5	PG-TDSON-8	052N08NS	-

## OptiMOS<sup>TM</sup>5 Power-Transistor, 80 V BSC052N08NS5



### **Table of Contents**

escription	1
1aximum ratings	3
hermal characteristics	3
lectrical characteristics	4
lectrical characteristics diagrams	6
ackage Outlines	0
evision History	3
rademarks	3
nisclaimer	3

### OptiMOS<sup>™</sup>5 Power-Transistor, 80 V **BSC052N08NS5**



1 Maximum ratings at  $T_j = 25$  °C, unless otherwise specified

Table 2 Maximum ratings

Parameter	0 h a l	Values				
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Continuous drain current	I <sub>D</sub>	- - -	-	95 60 19	A	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C, $R_{\rm thJA}$ =50K/W <sup>1)</sup>
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	-	-	380	Α	<i>T</i> <sub>C</sub> =25 °C
Avalanche energy, single pulse <sup>3)</sup>	<b>E</b> AS	-	-	70	mJ	$I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 $\Omega$
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-
Power dissipation	P <sub>tot</sub>	-	-	83 2.5	W	T <sub>C</sub> =25 °C T <sub>A</sub> =25 °C, R <sub>thJA</sub> =50 K/W <sup>1)</sup>
Operating and storage temperature	$T_{\rm j},~T_{\rm stg}$	-55	-	150	°C	IEC climatic category; DIN IEC 68-1: 55/150/56

#### 2 Thermal characteristics

**Thermal characteristics** Table 3

Parameter	Symbol	Values			Unit	Note / Test Condition
Farameter	Symbol	Min.	Тур.	Max.	Ollit	Note / Test Condition
Thermal resistance, junction - case, bottom	R <sub>thJC</sub>	-	0.9	1.5	K/W	-
Thermal resistance, junction - case, top	R <sub>thJC</sub>	-	-	20	K/W	-
Device on PCB, 6 cm <sup>2</sup> cooling area <sup>1)</sup>	R <sub>thJA</sub>	-	-	50	K/W	-

 $<sup>^{1)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.  $^{2)}$  See figure 3 for more detailed information  $^{3)}$  See figure 13 for more detailed information

# OptiMOS<sup>™</sup>5 Power-Transistor, 80 V BSC052N08NS5



### 3 Electrical characteristics

Table 4 Static characteristics

Parameter	0		Value	S		
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	80	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA
Gate threshold voltage	V <sub>GS(th)</sub>	2.2	3.0	3.8	V	$V_{\rm DS}$ = $V_{\rm GS}$ , $I_{\rm D}$ =49 $\mu A$
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1 10	1 100	μA	V <sub>DS</sub> =80 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =80 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C
Gate-source leakage current	I <sub>GSS</sub>	-	10	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	4.4 6.3	5.2 7.6	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =47.5 A V <sub>GS</sub> =6 V, I <sub>D</sub> =23.8 A
Gate resistance <sup>1)</sup>	R <sub>G</sub>	-	1.1	1.7	Ω	-
Transconductance	g <sub>fs</sub>	38	76	-	S	$ V_{DS}  > 2 I_D R_{DS(on)max}, I_D = 47.5 A$

**Table 5** Dynamic characteristics

Parameter	C: mala al	Values				
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance <sup>1)</sup>	C <sub>iss</sub>	-	2200	2900	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =40 V, f=1 MHz
Output capacitance <sup>1)</sup>	Coss	-	370	480	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =40 V, f=1 MHz
Reverse transfer capacitance <sup>1)</sup>	C <sub>rss</sub>	-	18	32	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =40 V, <i>f</i> =1 MHz
Turn-on delay time	$t_{\sf d(on)}$	-	12	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =47.5 A, $R_{\rm G,ext}$ =3 $\Omega$
Rise time	t <sub>r</sub>	-	7	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =47.5 A, $R_{\rm G,ext}$ =3 $\Omega$
Turn-off delay time	$t_{ m d(off)}$	-	19	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =47.5 A, $R_{\rm G,ext}$ =3 $\Omega$
Fall time	t <sub>f</sub>	-	5	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =47.5 A, $R_{\rm G,ext}$ =3 $\Omega$

Table 6 Gate charge characteristics<sup>2)</sup>

Parameter	Cumbal		Values			Note / Took Condition
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Gate to source charge	$Q_{gs}$	-	11	-	nC	$V_{DD}$ =40 V, $I_{D}$ =47.5 A, $V_{GS}$ =0 to 10 V
Gate charge at threshold	$Q_{g(th)}$	-	6.2	-	nC	$V_{DD}$ =40 V, $I_{D}$ =47.5 A, $V_{GS}$ =0 to 10 V
Gate to drain charge <sup>1)</sup>	$Q_{ m gd}$	-	7.1	11	nC	$V_{DD}$ =40 V, $I_{D}$ =47.5 A, $V_{GS}$ =0 to 10 V
Switching charge	Q <sub>sw</sub>	-	12	-	nC	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =47.5 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total <sup>1)</sup>	$Q_g$	-	32	40	nC	$V_{DD}$ =40 V, $I_{D}$ =47.5 A, $V_{GS}$ =0 to 10 V
Gate plateau voltage	V <sub>plateau</sub>	-	4.9	-	V	$V_{DD}$ =40 V, $I_{D}$ =47.5 A, $V_{GS}$ =0 to 10 V
Gate charge total, sync. FET	Q <sub>g(sync)</sub>	-	27	-	nC	V <sub>DS</sub> =0.1 V, V <sub>GS</sub> =0 to 10 V
Output charge <sup>1)</sup>	Qoss	-	39	52	nC	V <sub>DD</sub> =40 V, V <sub>GS</sub> =0 V

 $<sup>^{1)}</sup>$  Defined by design. Not subject to production test.  $^{2)}$  See "Gate charge waveforms" for parameter definition

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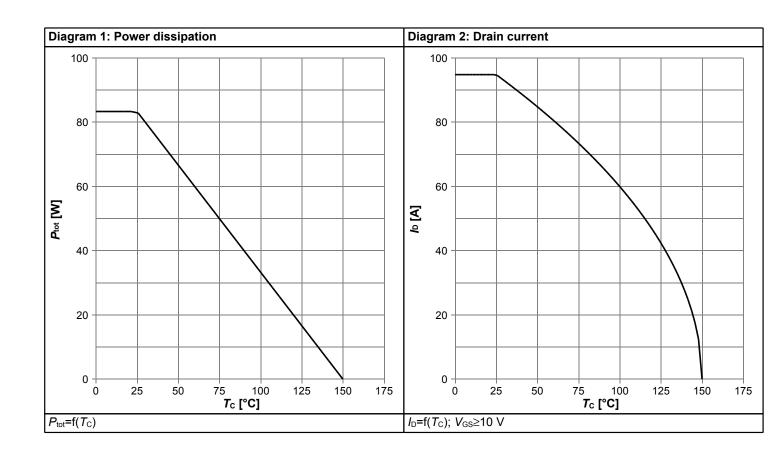


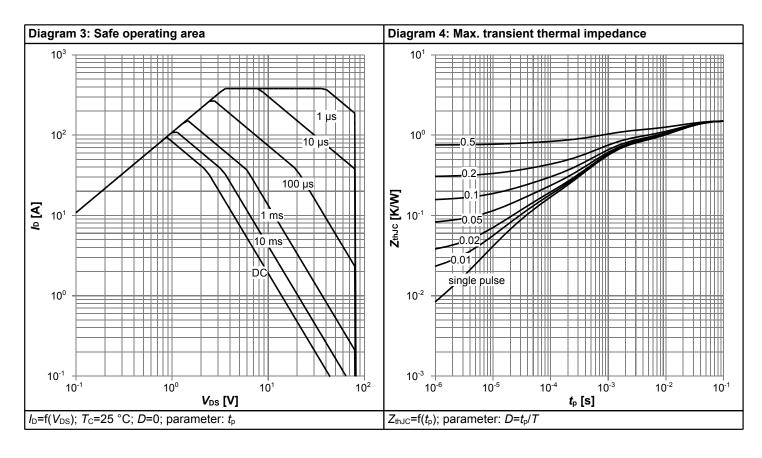
### Table 7 Reverse diode

Davamatav	Cumbal		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continuous forward current	Is	-	-	76	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode pulse current	I <sub>S,pulse</sub>	-	-	380	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode forward voltage	V <sub>SD</sub>	-	0.89	1.1	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =47.5 A, T <sub>j</sub> =25 °C	
Reverse recovery time <sup>1)</sup>	t <sub>rr</sub>	-	37	74	ns	$V_R$ =40 V, $I_F$ =47.5A, $di_F/dt$ =100 A/ $\mu$ s	
Reverse recovery charge <sup>1)</sup>	Qrr	-	35	70	nC	V <sub>R</sub> =40 V, I <sub>F</sub> =47.5A, d <i>i</i> <sub>F</sub> /d <i>t</i> =100 A/μs	

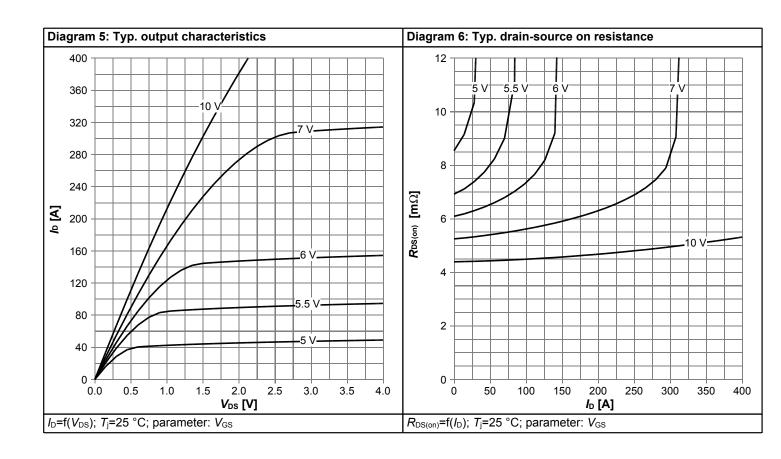


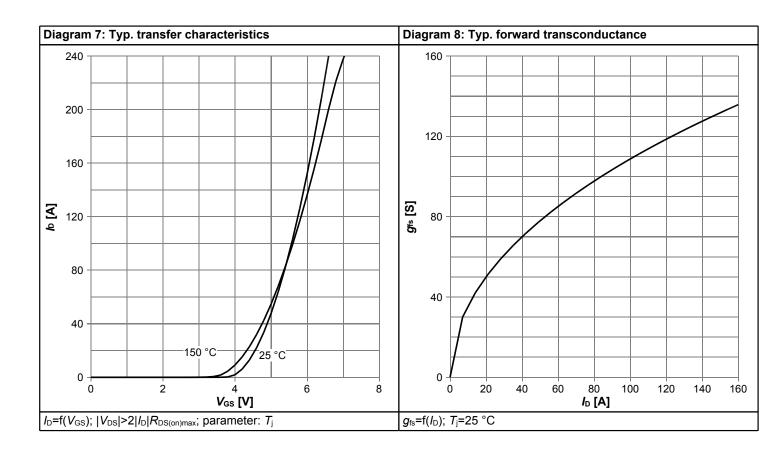
### 4 Electrical characteristics diagrams



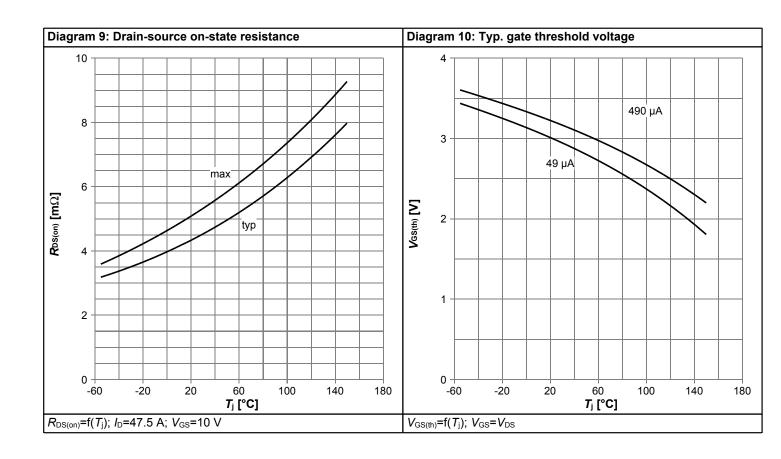


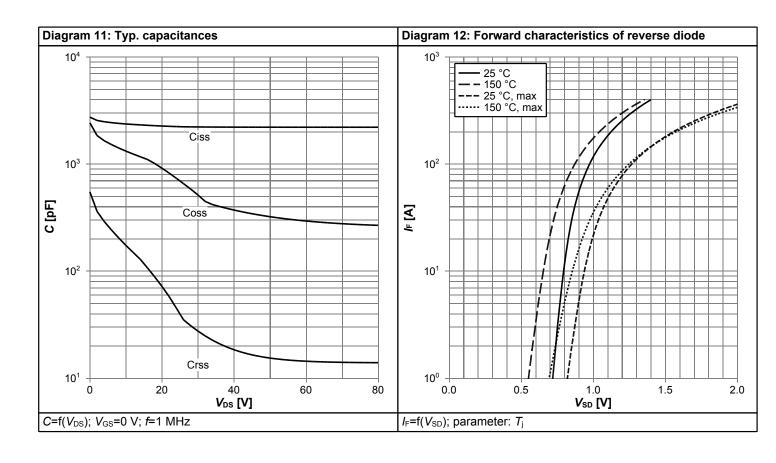




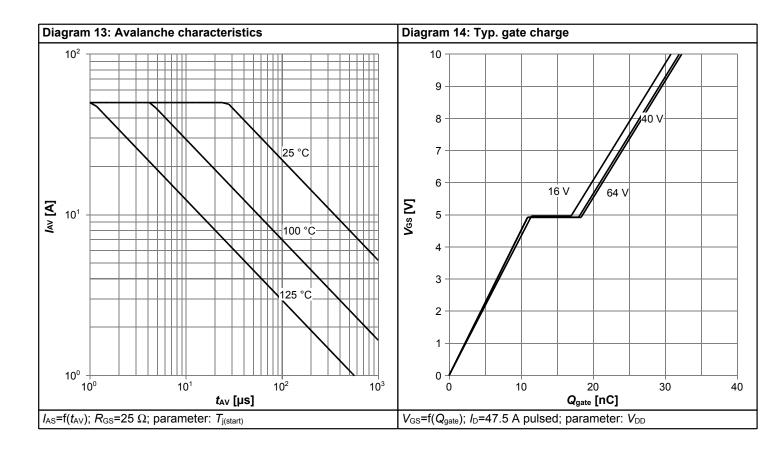


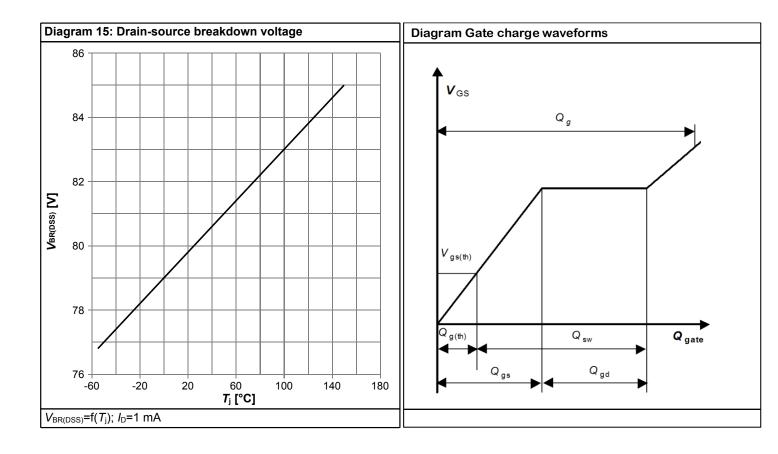






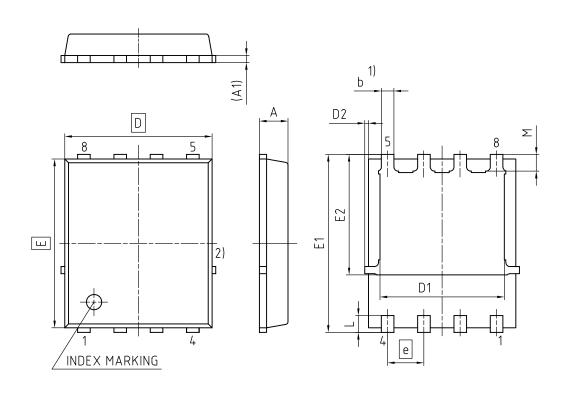








### 5 Package Outlines



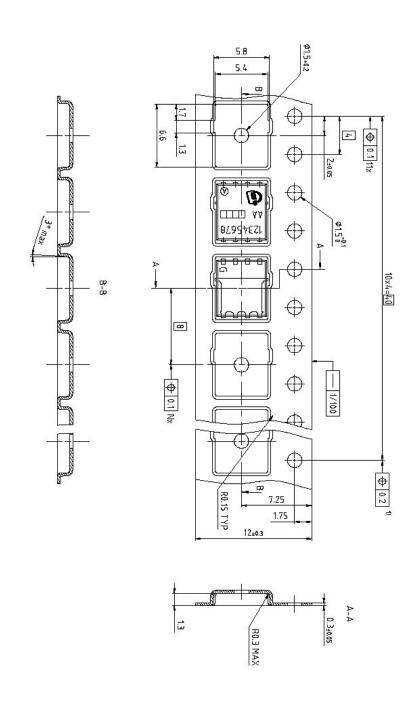
1) EXCLUDING MOLD FLASH
2) REMOVAL ON MOLD GATE
INTRUSION 0.1 MM
PROTRUSION 0.1 MM
LEAD LENGTH UP TO ANTI FLASH LINE
ALL METAL SURFACES ARE PLATED, EXCEPT AREA OF CUT

DIMENSION	MILLIM	ETERS			
DIMENSION	MIN.	MAX.			
Α	0.90	1.20			
A1	0.15	0.35			
b	0.34	0.54			
D	4.80	5.35			
D1	3.90	4.40			
D2	0.03	0.23			
E	5.70	6.10			
E1	5.90	6.42			
E2	3.88	4.31			
е	1.27				
L	0.45	0.71			
М	0.45	0.69			

Z8B00003332
REVISION 07
SCALE 10:1
0 1 2 3mm
EUROPEAN PROJECTION
ISSUE DATE 06.06.2019

Figure 1 Outline PG-TDSON-8, dimensions in mm





Dimension in mm

Figure 2 Outline Tape (TDSON-8)



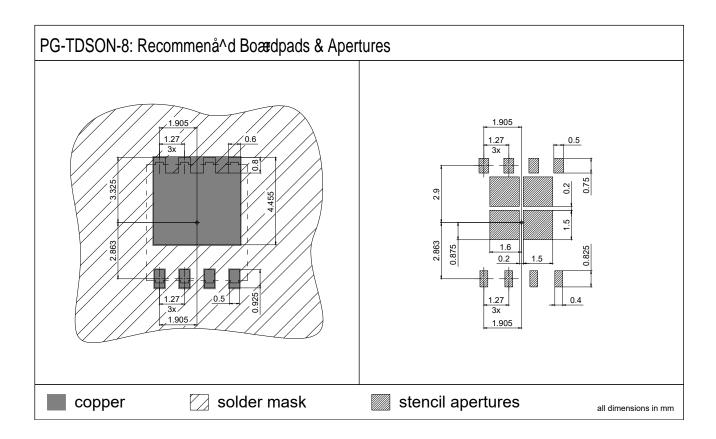


Figure 3 Outline Boardpads (TDSON-8), dimensions in mm

# OptiMOS $^{\text{TM}}$ 5 Power-Transistor , 80 V BSC052N08NS5



#### Revision History

#### BSC052N08NS5

Revision: 2019-10-31, Rev. 2.1

#### **Previous Revision**

Revision	Date	Subjects (major changes since last revision)
2.0	2014-12-27	Release of final version
2.1	2019-10-31	Update package drawings

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